# Cleanliness Evaluation as per IEST-STD-CC1246D

CLEMEX intelligent microscopy

| | | | |
|---|---|---|---|
| **Sample name:** | ABC123 | **Calibration:** | 1.4784 µm/pixel |
| **Analyst:** | John Smith | **Magnification:** | 50x |
| **Sample Size:** | 4 inch wafer | **# Fields:** | 489 |
| **Number of Samples:** | 1 | **Target Level:** | 100 |
| **ID of replicate samples:** | | | |

| | | | |
|---|---|---|---|
| **Date procured:** | 2009-Jun-11 | **Date tested:** | 2009-Jun-11 |

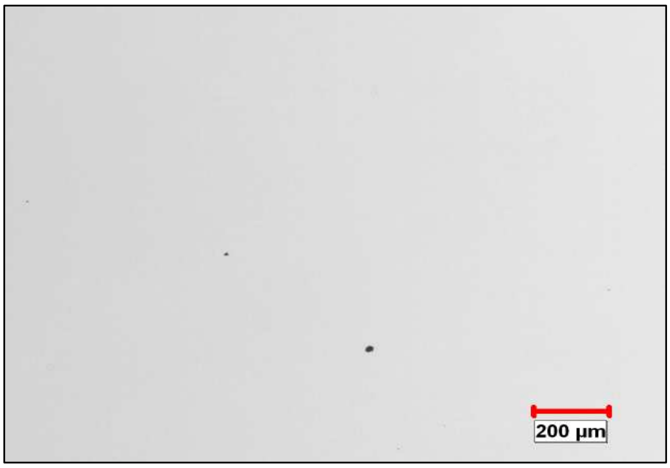
**Aditionnal information:**
Note: Complete surface analyzed
Operating condition of item during test procurement.
Environment in which sample was taken
Equipment used to take sample
Method used to obtain sample.
Method used to perform test

**Results**

| | | Normalized to 0.1 m2 |
|---|---|---|
| **Total area analyzed:** | 1386692127 mic2 | 0.1 m2 |
| **Total particle count:** | 23 | 1658.6 |
| **Total particle area:** | 985.735611 mic2 | 71085.4 mic2 |

| | |
|---|---|
| **Percent Area Coverage:** | 0.000071 % |
| **UCL** | 34.5 |
| **LCL** | 15.3 |

| Particle Size (mic) | Max. concentration for 0.1 m2 | Count (normalized) | Over |
|---|---|---|---|
| 5 | 1784.8 | 1658.6 | no |
| 15 | 265.0 | 216.3 | no |
| 25 | 78.4 | 72.1 | no |
| 50 | 10.7 | 0.0 | no |
| 100 | 1.0 | 0.0 | no |



Largest particle found.